

Enhancement Mode P-Channel Power MOSFET

SOT23/PMOS/-40V/ \pm 20V/-1.6V/-5A/62m Ω

Rev1.0





-40V, 62mΩ, -5A, Single P-Channel

1.Features

- -40V MOSFET technology
- Low on-state resistance
- Fast switching
- Vgs±20V

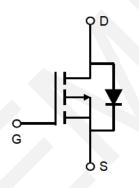
V_{DS}	$R_{DS(on)}$ Typ.	I _D Max.	
-40V	62mΩ @ -10V	5 A	
	79mΩ @ -4.5V	-5A	

2.Applications

- Power Switching Application
- Load Switching



Pin Description



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WX05P04	05P04	SOT23	3,000	120,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	$V_{ extsf{DSS}}$	-40	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	I _D	-5	А
Drain Current (Pulse), PW≤300μs	I _{DP}	-20	А
Total Dissipation	P_{D}	1.2	W
Junction Temperature	Tj	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	103	°C/W

Note 2: When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.



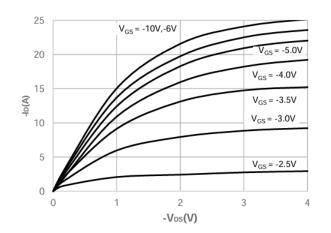
6.Electrical Characteristics at Ta=25°C (Note 3)

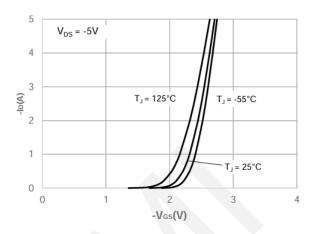
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = -250 \mu A, V_{GS} = 0V$	-40	-	-	٧
Zero-Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -40V, V_{GS} = 0V$	ı	·	-1	μΑ
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V$, $V_{DS} = 0V$	1	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _{DS} =-250μA	-1	-1.6	-2.5	V
Static Drain to Source On-State	Б	$I_D = -3A$, $V_{GS} = 10V$	ı	62	80	mΩ
Resistance	$R_{DS(on)}$	I _D = -2A, V _{GS} = 4.5V	-	79	105	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	546	-	pF
Output Capacitance	C_{oss}	V _{DS} =-20V,	-	52	-	pF
Reverse Transfer Capacitance	C_{rss}	Frequency=1.0MHz	1	43	-	pF
Turn-ON Delay Time	t _{d(on)}		1	8	-	ns
Rise Time	t _r	V _{DD} = -20V, I _D =-2A,	-	13	-	ns
Turn-OFF Delay Time	$t_{\text{d(off)}}$	V_{GS} = -10V, R_{GEN} = 3Ω	-	16	-	ns
Fall Time	t _f		-	6	-	ns
	Q_g	V _{DS} = -20V,	-	11	-	nC
Total Gate Charge	Q_{gs}	V _{GS} =0 to 10V,	-	1.8	-	nC
	Q_{gd}	I _D = -2A	-	1.9	-	nC
Diode Forward Voltage	V _{FSD}	I _S = -3A, V _{GS} = 0	0.5	-	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

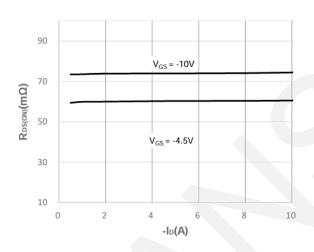


7. Typical Electrical and Thermal Characteristics

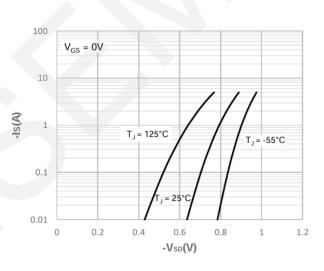




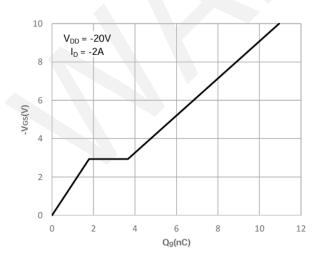
Output Characteristics



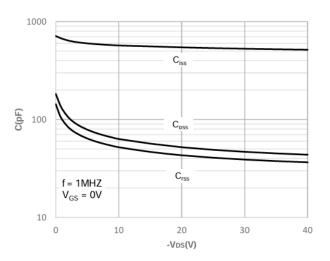
Transfer Characteristics



Drain-Source On-Resistance



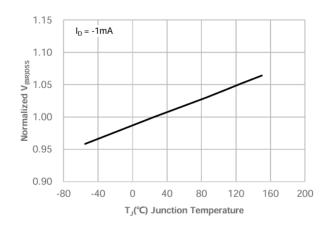
Body Diode Characteristics

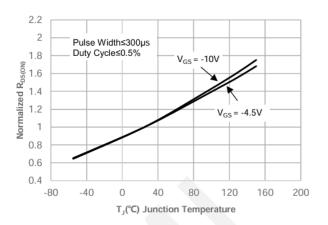


Gate Charge Characteristics

Capacitance Characteristics

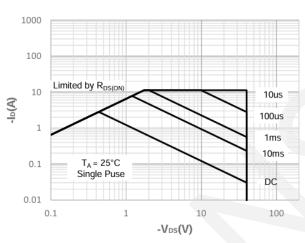


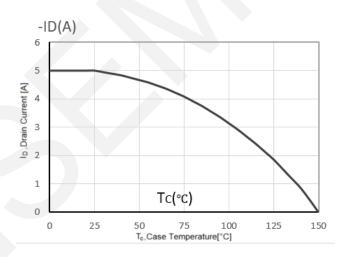




Normalized Breakdown voltage vs. Junction Temperature

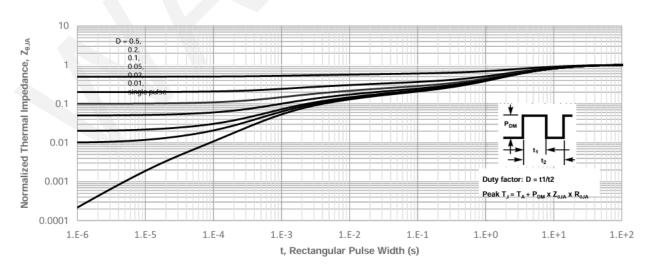
Normalized on Resistance vs. Junction Temperature





Maximum Safe Operating Area

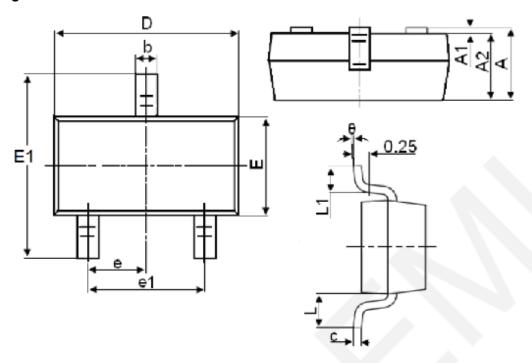
Maximum Continuous Drian Current vs. Ambient Temperature



Normalized Maximum Transient Thermal Impedance



8.Package Dimensions



Symbol	Dimensions in Millimeters			
	MIN.	TYP.	MAX.	
Α	0.900		1.150	
A1	0.000		0.100	
A2	0.900		1.050	
b	0.300		0.500	
С	0.080		0.150	
D	2.800		3.000	
E	1.200		1.400	
E1	2.250		2.550	
е		0.950		
e1	1.800		2.000	
L		0.550		
L1	0.300		0.500	
θ	0°		8°	



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